Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/677,075	KONNO, TAKESHI	
Examiner	Art Unit	
Nam V. Nguyen	2635	•

Nam V. Nguyen

SEARCHED				
Class	Subclass	Date	Examiner	
340	5.61	3/7/2006	NN	
340	5.6+	3/7/2006	NN	
340	5.7+	3/7/2006	NN	
340	10.1	3/7/2006	NN	
340	10.3+	3/7/2006	NN	
340	10.4+	3/7/2006	NN	
340	426	3/7/2006	NN	
381	86	3/7/2006	NN	
343	713	3/7/2006	NN	
343	711	3/7/2006	NN	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	×			

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Search East: USPAT; US-PUB; EPO; JPO; Derwent. (UPDATED SEARCH)	3/7/2006	NN
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